



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

11
NJ
1/16/03

In re patent application of

Hamid K. Aghajan

Serial No.: 09/365,517

Filed: August 2, 1999

For: Two-Dimensional Scatter Plot
Technique for Defect Detection

Group Art Unit: 2625

Examiner: S. C. Chawan

Date: January 3, 2003

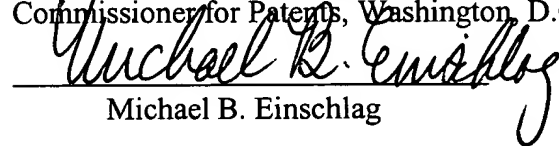
RECEIVED

JAN 14 2003

Technology Center 2600

CERTIFICATE OF MAILING under 37 C.F.R. 1.8(a)

I hereby certify that this correspondence is being deposited on January 3, 2003 with the United States Postal Service as first class mail, with sufficient postage, in an envelope addressed to Commissioner for Patents, Washington, D.C. 20231.


Michael B. Einschlag

January 3, 2003
Date of Signature

Commissioner for Patents
Washington, D.C. 20231

Sir:

This is in response to the outstanding Office Action mailed November 6, 2002.